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Application/Control No.	Applicant(s)/Patent under Reexamination
10/027,657	MEYER ET AL.
Examiner	Art Unit
Jia Lu	2611

SEARCHED					
Class	Subclass	Date	Examiner		
375	347	1/18/2007	JL		
375	346	1/18/2007	JL		
370	442	1/18/2007	JL		
370	480	1/18/2007	JL		
370	347	1/18/2007	JL		
375	344	1/18/2007	JL		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
ALL EAST DATABASES	1/18/2007	JL		